

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	11	richard-Taylor.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:12
L2	0	monitierth-melvin.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:11
L3	10	zimmerman-gary.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:32
L4	3728	((volatile adj2 memor\$3) or RAM or DRAM) near3 check\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:35
L5	58	((volatile adj2 memor\$3) or RAM or DRAM) near3 checker	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:35
L7	152	((volatile adj2 memor\$3) or RAM or DRAM) and (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:38
L8	45	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3 and (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:39
L10	12	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3 and (detect\$4 near3 (soft adj2 error\$1)) and (timer)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:40
L11	8	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3 and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and test\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L12	0	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3 and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:40
L13	4	((volatile adj2 memor\$3) or RAM or DRAM or memory) and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:42
L14	6	((volatile adj2 memor\$3) or RAM or DRAM or memory) and (detect\$4 near3 (soft adj2 error\$1)) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:45

L15	31	((((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (detect\$4 near3 (soft adj2 error\$1)) and (self near3 test\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:46
L16	73	((((volatile adj2 memor\$3) or RAM or DRAM or memory)) and ((self near3 test\$4) or (self-tester)) and (recovery adj3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:48
L17	3	((((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (((self near3 test\$4) or (self-tester)) near15 detect\$4) and (recovery adj3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:52
L18	15	((((volatile adj2 memor\$3) or RAM or DRAM or memory) near5 checker) and (((self near3 test\$4) or (self-tester)) near15 detect\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:51
L19	5	((((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (((self near3 test\$4) or (self-tester)) near15 detect\$4) and (recov\$4 near3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:14
L20	11	((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L21	0	(((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))) and CRC	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L22	0	(((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))) and (CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:54
L24	896	((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer near3 control\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:55
L25	219	((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56
L26	210	((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller) and process\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56
L27	129	((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller) and processor	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56

L28	1	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller) and processor and (recovery near2 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:57
L29	7	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller) and (recovery near2 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:57
L30	114	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) and (recov\$4 near3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:16
L31	14	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:16
L32	13	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1)) and (detect\$4 or check\$3 or CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:17
L33	13	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1)) and (detect\$4 or check\$3 or CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:17


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

Search Results

[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(((memory<near/3>(checker<or>detector))<and>testing)<in>metadata))"

[Email](#)

Your search matched 10 of 1174497 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

[» View Session History](#)[» New Search](#)[» Key](#)

Modify Search

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

IEEE JNL IEEE Journal or Magazine

IEEE JNL IEEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEEE CNF IEEE Conference Proceeding

IEEE STD IEEE Standard

Select Article Information

- ☐ 1. **PRISM-a tool for modelling proton energy deposition in semi-conductor material:**
Oldfield, M.K.; Underwood, C.I.;
Nuclear Science, IEEE Transactions on
Volume 43, Issue 6, Dec. 1996 Page(s):2715 - 2723
[AbstractPlus](#) | Full Text: [PDF\(780 KB\)](#) IEEE JNL
- ☐ 2. **A flexible analog memory address list manager for PHENIX**
Ericson, M.N.; Musrock, M.S.; Britton, C.L., Jr.; Walker, J.W.; Winterberg, A.L.; Young,
Nuclear Science, IEEE Transactions on
Volume 43, Issue 3, June 1996 Page(s):1629 - 1633
[AbstractPlus](#) | Full Text: [PDF\(452 KB\)](#) IEEE JNL
- ☐ 3. **A 1006 element hybrid silicon pixel detector with strobed binary output**
Anghinolfi, F.; Aspell, P.; Bass, K.; Beusch, W.; Bosisio, L.; Boutonnet, C.; Burger, P.; Chesi, E.; Claeys, C.; Clemens, J.C.; Cohen Solal, M.; Debusschere, I.; Delpierre, P.; Dierickx, B.; Enz, C.C.; Focardi, E.; Forti, F.; Gally, Y.; Glaser, M.; Gys, T.; Habrard, M. E.H.M.; Hermans, L.; Hurst, R.; Inzani, P.; Jaeger, J.J.; Jarron, P.; Krummenacher, F.; Lenti, V.; Manzari, V.; Meddeler, G.; Morando, M.; Munns, A.; Nava, F.; Navach, F.; Ne G.; Pellegrini, F.; Pengg, F.; Perego, R.; Pindo, M.; Potheau, R.; Quercigh, E.; Redaelli Sauvage, D.; Segato, G.; Simone, S.; Stefanini, G.; Tonelli, G.; Vanstraelen, G.; Vegni, Viertel, G.M.; Waisbard, J.;
Nuclear Science, IEEE Transactions on
Volume 39, Issue 4, Aug 1992 Page(s):654 - 661
[AbstractPlus](#) | Full Text: [PDF\(992 KB\)](#) IEEE JNL
- ☐ 4. **Results of radiation tests performed on the ISOCAM infrared detector array**
Agnese, P.; Engelmann, J.J.; Mottier, P.;
Nuclear Science, IEEE Transactions on
Volume 38, Issue 4, Aug. 1991 Page(s):953 - 963
[AbstractPlus](#) | Full Text: [PDF\(704 KB\)](#) IEEE JNL
- ☐ 5. **Performance of the electronics for the liquid argon calorimeter system of the SL**
Vella, E.; Abt, I.; Haller, G.M.; Honma, A.;
Nuclear Science, IEEE Transactions on
Volume 36, Issue 1, Feb. 1989 Page(s):822 - 825
[AbstractPlus](#) | Full Text: [PDF\(292 KB\)](#) IEEE JNL

- ☐ 6. **Comparison of known signal detection schemes under a weakly dependent noise**
Kim, T.; Yun, J.S.; Song, I.; Na, Y.J.;
Vision, Image and Signal Processing, IEE Proceedings-
Volume 141, Issue 5, Oct. 1994 Page(s):303 - 310
[AbstractPlus](#) | Full Text: [PDF\(432 KB\)](#) [IEEE JNL](#)

- ☐ 7. **Reducing power consumption in memory ECC checkers**
Ghosh, S.; Basu, S.; Touba, N.A.;
Test Conference, 2004. Proceedings. International
2004 Page(s):1322 - 1331
[AbstractPlus](#) | Full Text: [PDF\(937 KB\)](#) [IEEE CNF](#)

- ☐ 8. **Asymptotic performance comparison of known signal detection schemes in weak noise**
Taehyun Kim; Jin Seon Yun; Sun Yong Kim; Ickho Song;
Military Communications Conference, 1994. MILCOM '94. Conference Record, 1994 IE
2-5 Oct. 1994 Page(s):276 - 280 vol.1
[AbstractPlus](#) | Full Text: [PDF\(276 KB\)](#) [IEEE CNF](#)

- ☐ 9. **Finite sample-size performance of known signal detectors in a weakly dependent noise**
Taehyun Kim; Jin Seon Yun; Young Kweon Ryu; Ickho Song;
Electrical and Computer Engineering, 1994. Conference Proceedings. 1994 Canadian
25-28 Sept. 1994 Page(s):288 - 291 vol.1
[AbstractPlus](#) | Full Text: [PDF\(244 KB\)](#) [IEEE CNF](#)

- ☐ 10. **A flexible analog memory address list manager for PHENIX**
Ericson, M.N.; Musrock, M.S.; Britton, C.L., Jr.; Walker, J.W.; Wintenberg, A.L.; Young,
M.D.;
Nuclear Science Symposium and Medical Imaging Conference Record, 1995., 1995 IE
Volume 1, 21-28 Oct. 1995 Page(s):5 - 9 vol.1
[AbstractPlus](#) | Full Text: [PDF\(440 KB\)](#) [IEEE CNF](#)

[View Selected Items](#)

indexed by
 Inspec

[Help](#) [Contact Us](#) [Privacy & Policy](#)

© Copyright 2005 IEEE - All rights reserved.


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

Search Results

BROWSE

SEARCH

IEEE XPLORE GUIDE

Results for "(((memory<near/3>(check<or>detection))<and>testing)<in>metadata)"

Your search matched 55 of 1174497 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

» [View Session History](#)» [New Search](#)

» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

Modify Search

☐ Check to search only within this results set
Display Format: ☒ Citation ☐ Citation & Abstract

Select Article Information

View: 1-

- | | |
|--------------------------|--|
| <input type="checkbox"/> | 1. Memory array architecture and decoding scheme for 3 V only sector erasable DIF memory
Kobayashi, S.; Nakai, H.; Kunori, Y.; Nakayama, T.; Miyawaki, Y.; Terada, Y.; Onoda, I
Hatanaka, M.; Miyoshi, H.; Yoshihara, T.;
Solid-State Circuits, IEEE Journal of
Volume 29, Issue 4, April 1994 Page(s):454 - 460
AbstractPlus Full Text: PDF (640 KB) IEEE JNL |
| <input type="checkbox"/> | 2. Interference faults testing for time switches
Tyszer, J.;
Communications, IEEE Transactions on
Volume 38, Issue 7, July 1990 Page(s):954 - 958
AbstractPlus Full Text: PDF (412 KB) IEEE JNL |
| <input type="checkbox"/> | 3. Concurrent error detection using watchdog processors-a survey
Mahmood, A.; McCluskey, E.J.;
Computers, IEEE Transactions on
Volume 37, Issue 2, Feb. 1988 Page(s):160 - 174
AbstractPlus Full Text: PDF (1372 KB) IEEE JNL |
| <input type="checkbox"/> | 4. Carry checking/parity prediction adders and ALUs
Nicolaidis, M.;
Very Large Scale Integration (VLSI) Systems, IEEE Transactions on
Volume 11, Issue 1, Feb. 2003 Page(s):121 - 128
AbstractPlus References Full Text: PDF (369 KB) IEEE JNL |
| <input type="checkbox"/> | 5. Automatic generation and compaction of March tests for memory arrays
Zarrineh, K.; Upadhyaya, S.J.; Chakravarty, S.;
Very Large Scale Integration (VLSI) Systems, IEEE Transactions on
Volume 9, Issue 6, Dec. 2001 Page(s):845 - 857
AbstractPlus References Full Text: PDF (296 KB) IEEE JNL |
| <input type="checkbox"/> | 6. Design and development paradigm for industrial formal verification CAD tools
Krishnamurthy, N.; Abadir, M.S.; Martin, A.K.; Abraham, J.A.;
Design & Test of Computers, IEEE
Volume 18, Issue 4, July-Aug. 2001 Page(s):26 - 35
AbstractPlus References Full Text: PDF (248 KB) IEEE JNL |

- ☐ **7. Testing SRAM-based content addressable memories**
Zhao, J.; Irrinki, S.; Puri, M.; Lombardi, F.;
Computers, IEEE Transactions on
Volume 49, Issue 10, Oct. 2000 Page(s):1054 - 1063
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(252 KB\)](#) IEEE JNL

- ☐ **8. A digital envelope detection filter for real-time operation**
Fritsch, C.; Ibanez, A.; Parrilla, M.;
Instrumentation and Measurement, IEEE Transactions on
Volume 48, Issue 6, Dec. 1999 Page(s):1287 - 1293
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(156 KB\)](#) IEEE JNL

- ☐ **9. Fault-secure parity prediction Booth multipliers**
Nicolaidis, M.; Duarte, R.O.;
Design & Test of Computers, IEEE
Volume 16, Issue 3, July-Sept. 1999 Page(s):90 - 101
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(220 KB\)](#) IEEE JNL

- ☐ **10. Random pattern testability of memory address logic**
Savir, J.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 17, Issue 12, Dec. 1998 Page(s):1310 - 1318
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(156 KB\)](#) IEEE JNL

- ☐ **11. Quick address detection of anomalous memory cells in a flash memory test structure**
Himeno, T.; Hazama, H.; Yaegashi, T.; Sakui, K.; Kanda, K.; Itoh, Y.; Miyamoto, J.;
Semiconductor Manufacturing, IEEE Transactions on
Volume 10, Issue 2, May 1997 Page(s):196 - 200
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(160 KB\)](#) IEEE JNL

- ☐ **12. Repairability/unrepairability detection technique for yield enhancement of VLSI in the presence of redundancy**
Shen, Y.-N.; Lombardi, F.;
Computers and Digital Techniques, IEE Proceedings-
Volume 137, Issue 2, Mar 1990 Page(s):133 - 136
[AbstractPlus](#) | Full Text: [PDF\(276 KB\)](#) IEEE JNL

- ☐ **13. Word-level symbolic simulation in processor verification**
Alizadeh, B.; Navabi, Z.;
Computers and Digital Techniques, IEE Proceedings-
Volume 151, Issue 5, 17 Sept. 2004 Page(s):356 - 366
[AbstractPlus](#) | Full Text: [PDF\(608 KB\)](#) IEEE JNL

- ☐ **14. Detecting faults in the peripheral circuits and an evaluation of SRAM tests**
van de Goor, Ad.J.; Hamdioui, S.; Wadsworth, R.;
Test Conference, 2004. Proceedings. International
2004 Page(s):114 - 123
[AbstractPlus](#) | Full Text: [PDF\(932 KB\)](#) IEEE CNF

- ☐ **15. Dynamic nonlinear distortion characterization of wireless radio transmitters**
Boumaiza, S.; Ghannouchi, F.M.;
Electron Devices for Microwave and Optoelectronic Applications, 2004. EDMO 2004. 1st
Symposium on
8-9 Nov. 2004 Page(s):92 - 95
[AbstractPlus](#) | Full Text: [PDF\(566 KB\)](#) IEEE CNF

- ☐ **16. SafeMem: Exploiting ECC-Memory for Detecting Memory Leaks and Memory Corruption Runs**
Feng Qin; Shan Lu; Yuanyuan Zhou;
High-Performance Computer Architecture, 2005. HPCA-11. 11th International Symposium
12-16 Feb. 2005 Page(s):291 - 302
[AbstractPlus](#) | Full Text: [PDF\(192 KB\)](#) IEEE CNF

- ☐ **17. Detection of control flow errors using signature and checking instructions**
Sosnowski, J.;
Test Conference, 1988. Proceedings. 'New Frontiers in Testing', International
12-14 Sept. 1988 Page(s):81 - 88
[AbstractPlus](#) | Full Text: [PDF\(640 KB\)](#) IEEE CNF

- ☐ **18. VLSI implementation of a self-checking self-exercising memory system**
Rennels, D.A.; Kim, H.;
Fault-Tolerant Computing, 1991. FTCS-21. Digest of Papers., Twenty-First International
25-27 June 1991 Page(s):170 - 177
[AbstractPlus](#) | Full Text: [PDF\(676 KB\)](#) IEEE CNF

- ☐ **19. On reducing test time and meeting deadlines in real-time systems**
Sarnaik, T.R.; Somani, A.K.;
Test Symposium, 1992. (ATS '92), Proceedings., First Asian (Cat. No.TH0458-0)
26-27 Nov. 1992 Page(s):151 - 156
[AbstractPlus](#) | Full Text: [PDF\(528 KB\)](#) IEEE CNF

- ☐ **20. Self-learning signature analysis for non-volatile memory testing**
Olivo, P.; Dalpasso, M.;
Test Conference, 1996. Proceedings., International
20-25 Oct. 1996 Page(s):303 - 308
[AbstractPlus](#) | Full Text: [PDF\(492 KB\)](#) IEEE CNF

- ☐ **21. DELFIM: error detection by thin memory protection**
Cunha, J.C.; Silva, J.G.;
EUROMICRO 96. 'Beyond 2000: Hardware and Software Design Strategies', Proceedings
EUROMICRO Conference
2-5 Sept. 1996 Page(s):343 - 350
[AbstractPlus](#) | Full Text: [PDF\(824 KB\)](#) IEEE CNF

- ☐ **22. Experimental evaluation of the fail-silent behaviour in programs with consistency**
Rela, M.Z.; Madeira, H.; Silva, J.G.;
Fault Tolerant Computing, 1996., Proceedings of Annual Symposium on
25-27 June 1996 Page(s):394 - 403
[AbstractPlus](#) | Full Text: [PDF\(912 KB\)](#) IEEE CNF

- ☐ **23. Dynamic test compaction for synchronous sequential circuits using static compaction techniques**
Pomeranz, I.; Reddy, S.M.;
Fault Tolerant Computing, 1996., Proceedings of Annual Symposium on
25-27 June 1996 Page(s):53 - 61
[AbstractPlus](#) | Full Text: [PDF\(740 KB\)](#) IEEE CNF

- ☐ **24. Achieving fault secureness in parity prediction arithmetic operators: general constructions and implementations**
Nicolaidis, M.; Manich, S.; Figueras, J.;
European Design and Test Conference, 1996. ED&TC 96. Proceedings
11-14 March 1996 Page(s):186 - 193
[AbstractPlus](#) | Full Text: [PDF\(696 KB\)](#) IEEE CNF